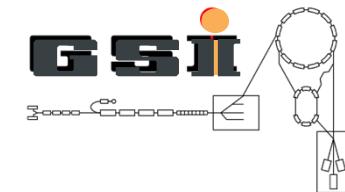


# Beam Induced Fluorescence

## Profile Monitoring for Targets and Transport



T. Dandl, T. Heindl, A. Ulrich, Physik Department TUM

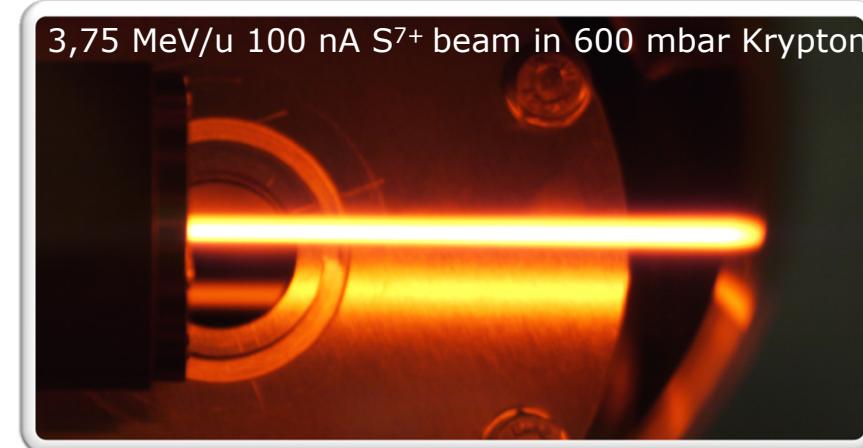
J. Egberts, J. Marroncle, T. Papaevangelou, CEA Saclay

C. Andre, F. Becker, C. Dorn, P. Forck, R. Haseitl, B. Walasek-Hoehne, GSI

HB2012

09/20/2012

GSI BI Department



# Outline

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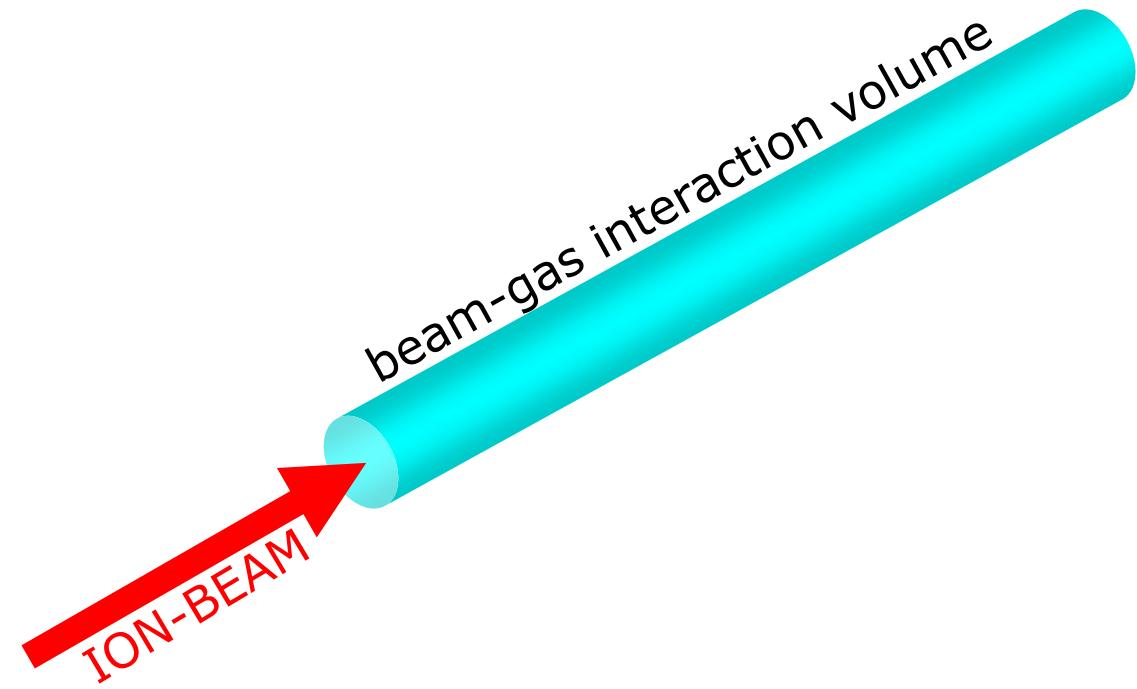


- Motivation & Introduction
  - Overview of common profile monitors
  - Benefit and principle of gas based profile measurement
  
- Physics – Results of Research
  - Comparison of BIF and IPM
  - Imaging spectroscopy in particular at high p
  - Issues for BIF imaging at high p
  - Reliable work around
  
- Summary - Outlook

# Common Profile Monitors for FAIR?

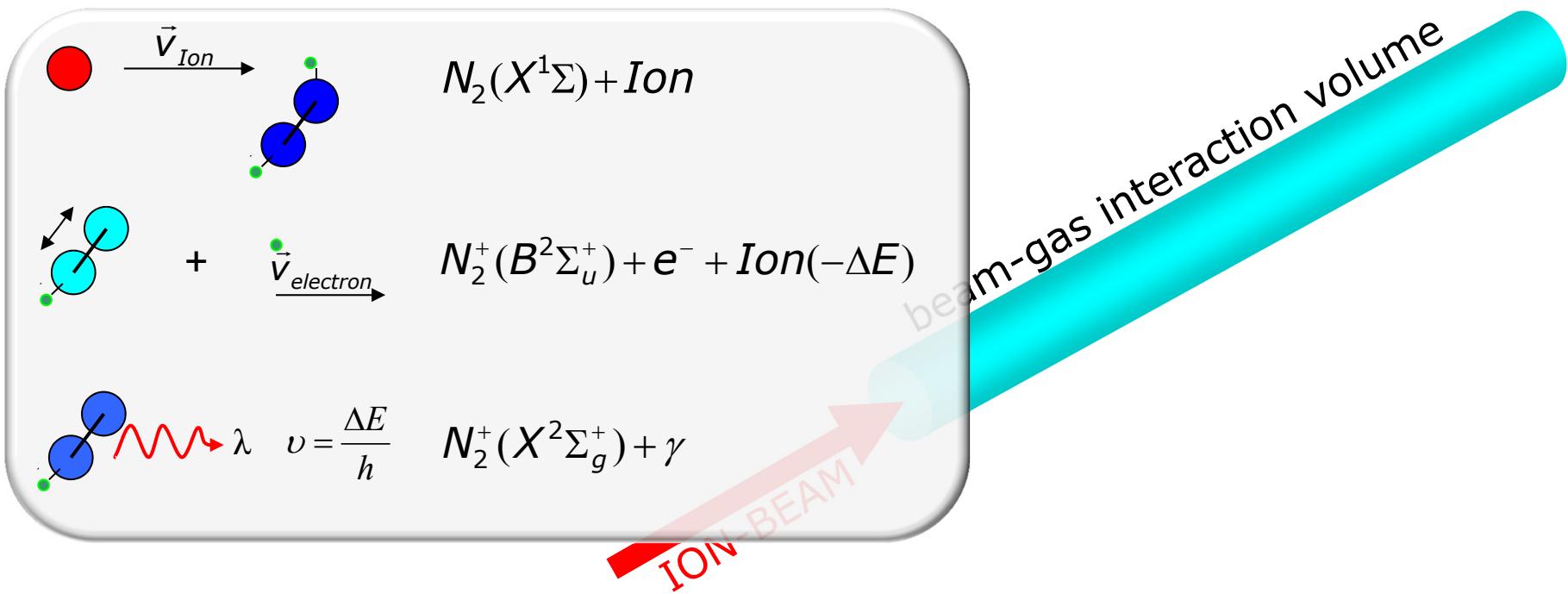


Device Name	PRO	CON
Scintillator Screen	2D image	Stability, accuracy, complex physics
OTR Screen	2D image	Scales with $q^2 \beta^2$
Wire Scanner	Sensitivity	Mechanical challenge, damage, thermionic $e^-$
SEM Grid	Sensitivity	Resolution, damage, thermionic $e^-$
Synchrotron Light	2D image	Needs magnetic field and relativistic particle
Laser Wire	2D image	Photon detachment works for $H^-$ ions
Gas Based Systems	Work @ FAIR conditions	Scales with $\sim q^2/\beta^2$



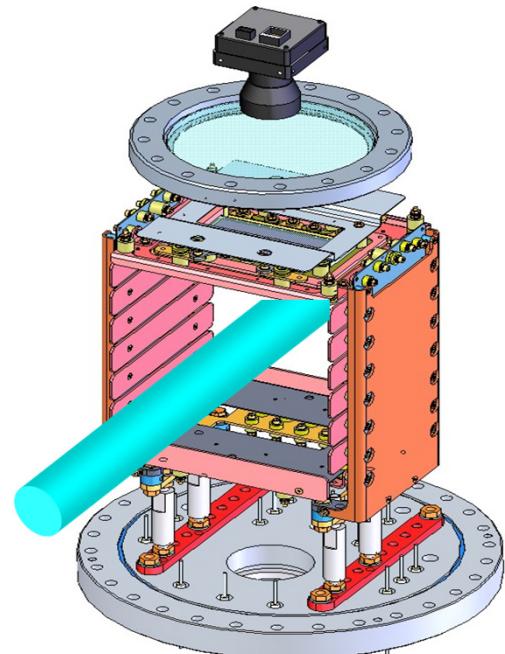
- N<sub>2</sub>-dominated for  $p \geq 10^{-8}$  mbar, H<sub>2</sub>-dominated for lower p
- Atomic collisions drive  $-dE/dx \rightarrow$  electronic stopping
- Processes to be observed: **ionization** and **fluorescence...**

# Gas-Based Detectors

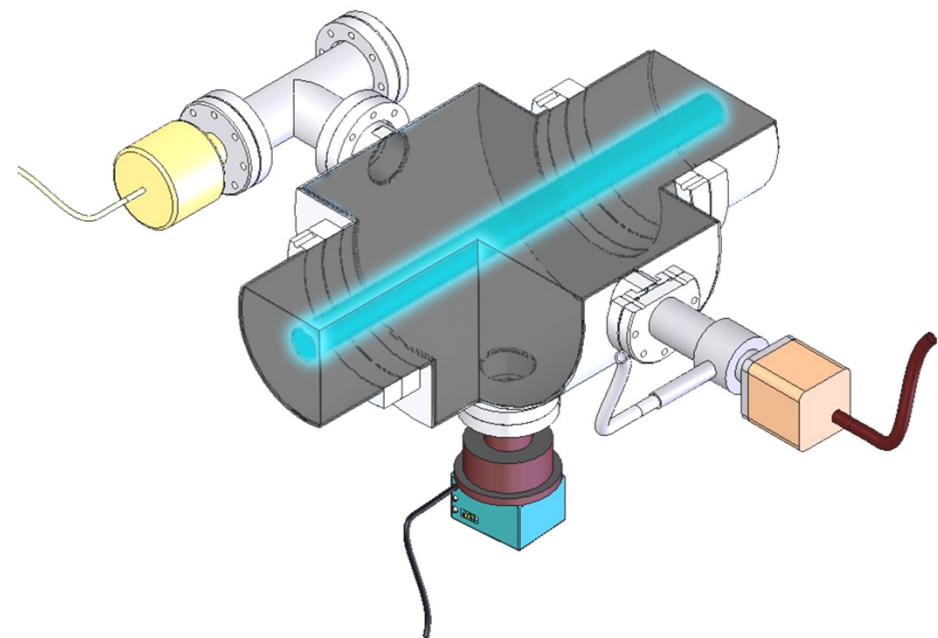


- $N_2$ -dominated for  $p \geq 10^{-8}$  mbar,  $H_2$ -dominated for lower  $p$
- Atomic collisions drive  $-dE/dx \rightarrow$  electronic stopping
- Processes to be observed: **ionization** and **fluorescence...**

## Ionization Profile Monitor



## Beam Induced Florescence (BIF) Monitor



[courtesy of T. Giacomini (GSI)]

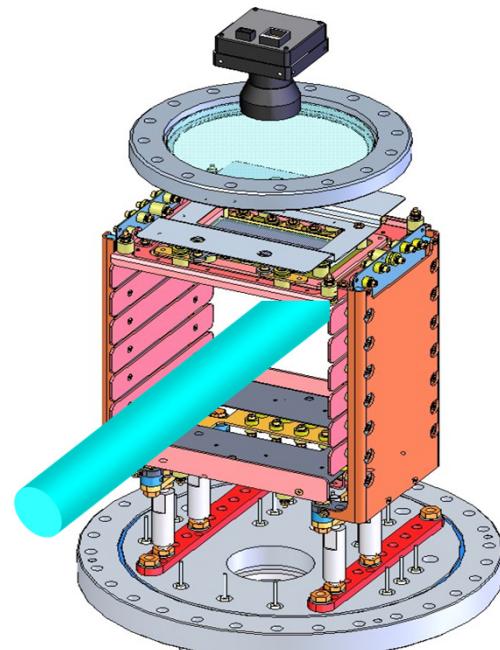
$$Y_{ionize} = \sigma_{ionize}(E, \bar{q}) N_{Ion} \Delta s P_{Det} \rho$$

$$Y_{photon} = \sigma_{photon}(E, \bar{q}) N_{Ion} \Delta s \Omega P_{Det} \rho$$

# IPM and BIF Monitor

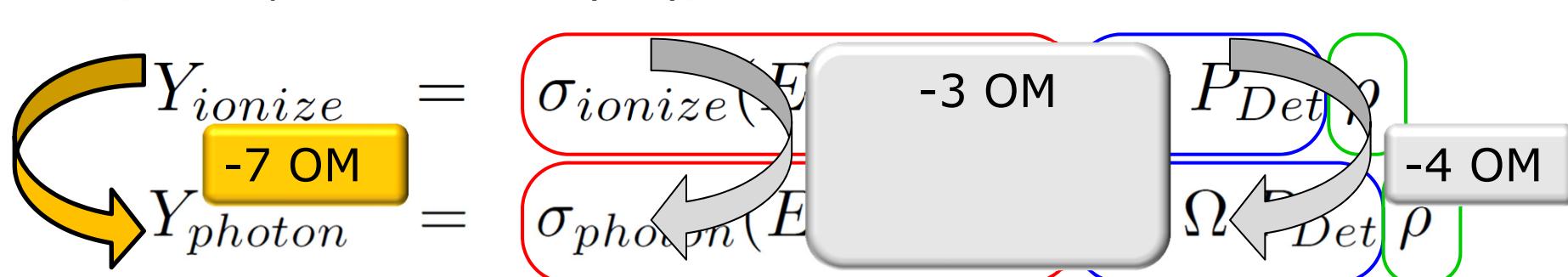
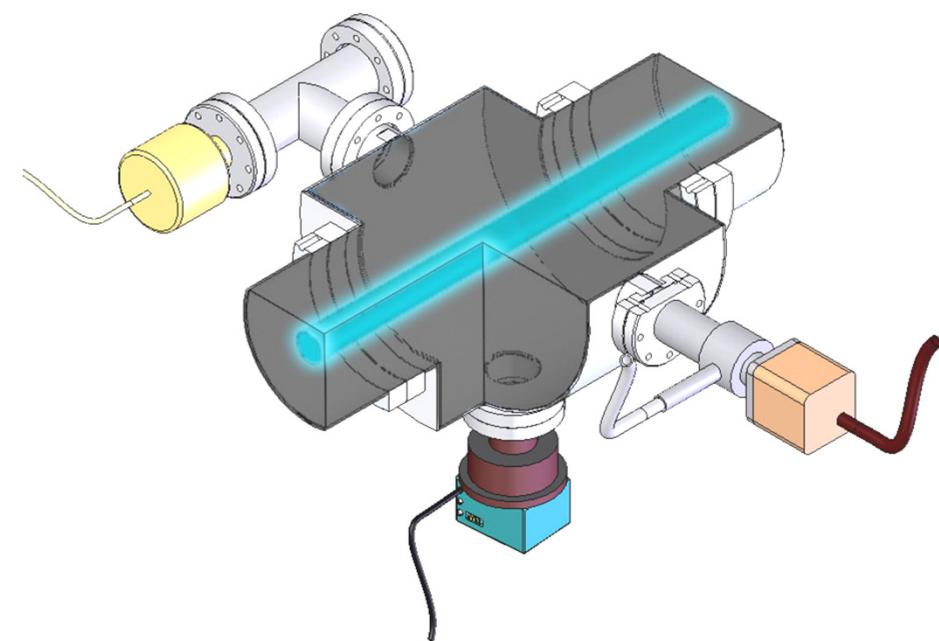


**Ionization Profile Monitor**

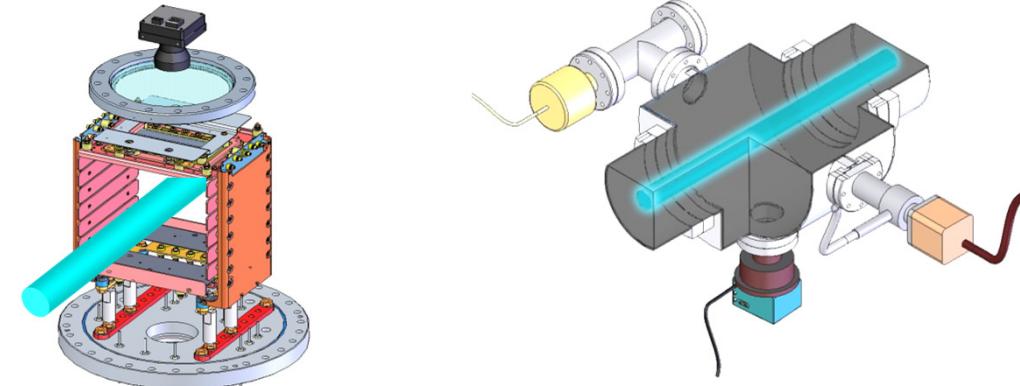


[courtesy of T. Giacomini (GSI)]

**Beam Induced Florescence**



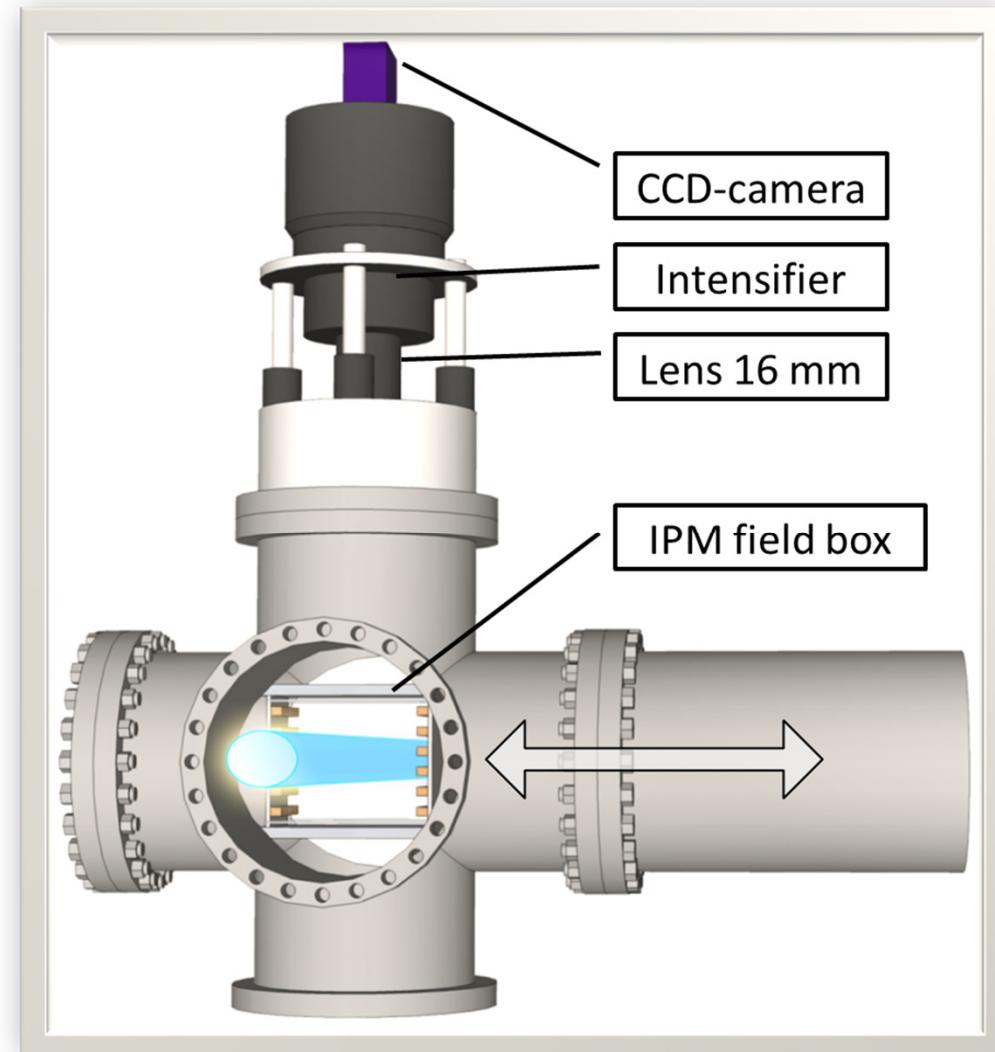
# IPM and BIF Monitor



Parameter	Evaluation IPM	Evaluation BIF
$p_{acc} = 10^{-12}$ to $10^{-9}$ mbar		gas jet @ RHIC BNL
$p_{tp} = 10^{-9}$ to $10^{-6}$ mbar		
$p_{tgt} = 10^{-3}$ to 1000 mbar	HV breakdown	?
high charge density	magnet system req.	only short lifetimes
spatial/temporal res.	$\geq 30 \mu\text{m}/\geq 10 \text{ ns}$	$\geq 30 \mu\text{m}/\geq 100 \text{ ns}$
limited insertion length	500 to $\sim 3000$ mm	200 mm
system complexity		

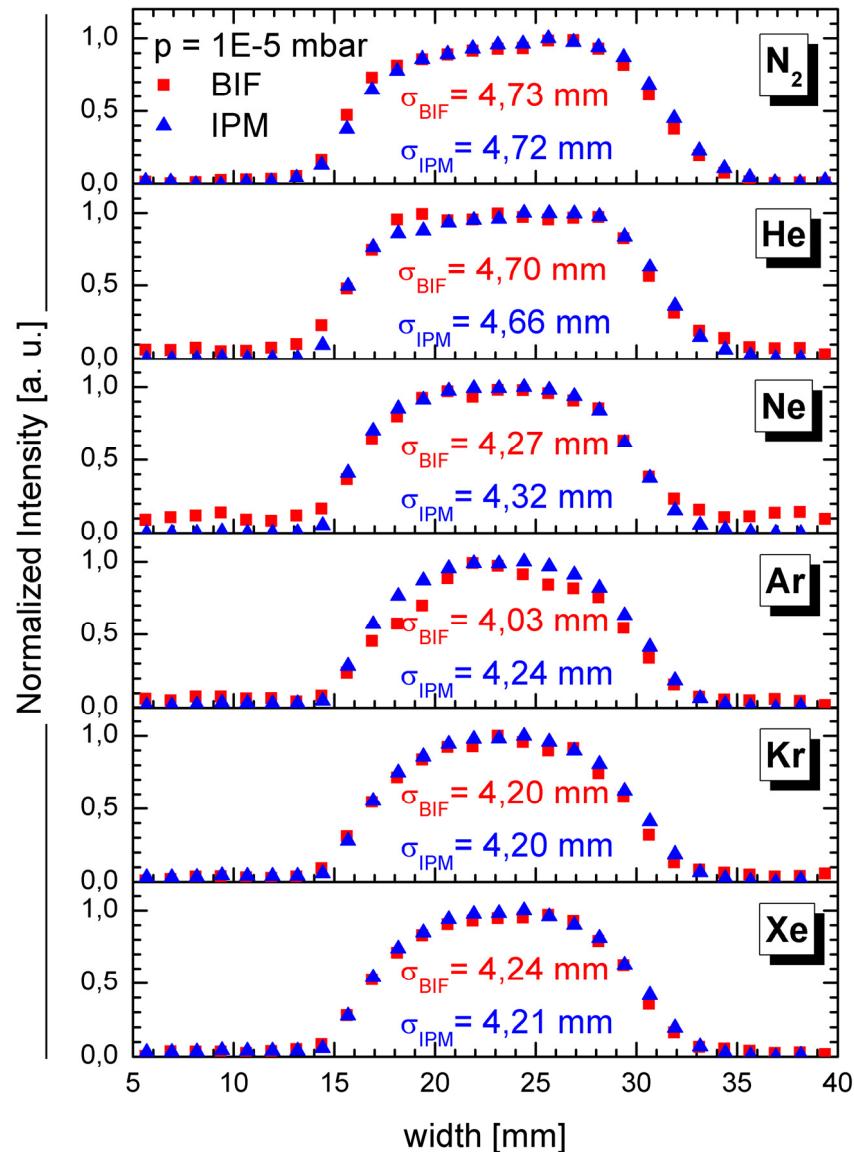
# BIF-IPM Comparison

- BIF and IPM mounted to observe the same plane
- BIF monitor as ICCD setup
- IPM with electrical readout on remote motor drive
- Chamber was blackened and connected to a gas dosing system
- Nitrogen and rare gases (high purity) were applied against constant pump flow



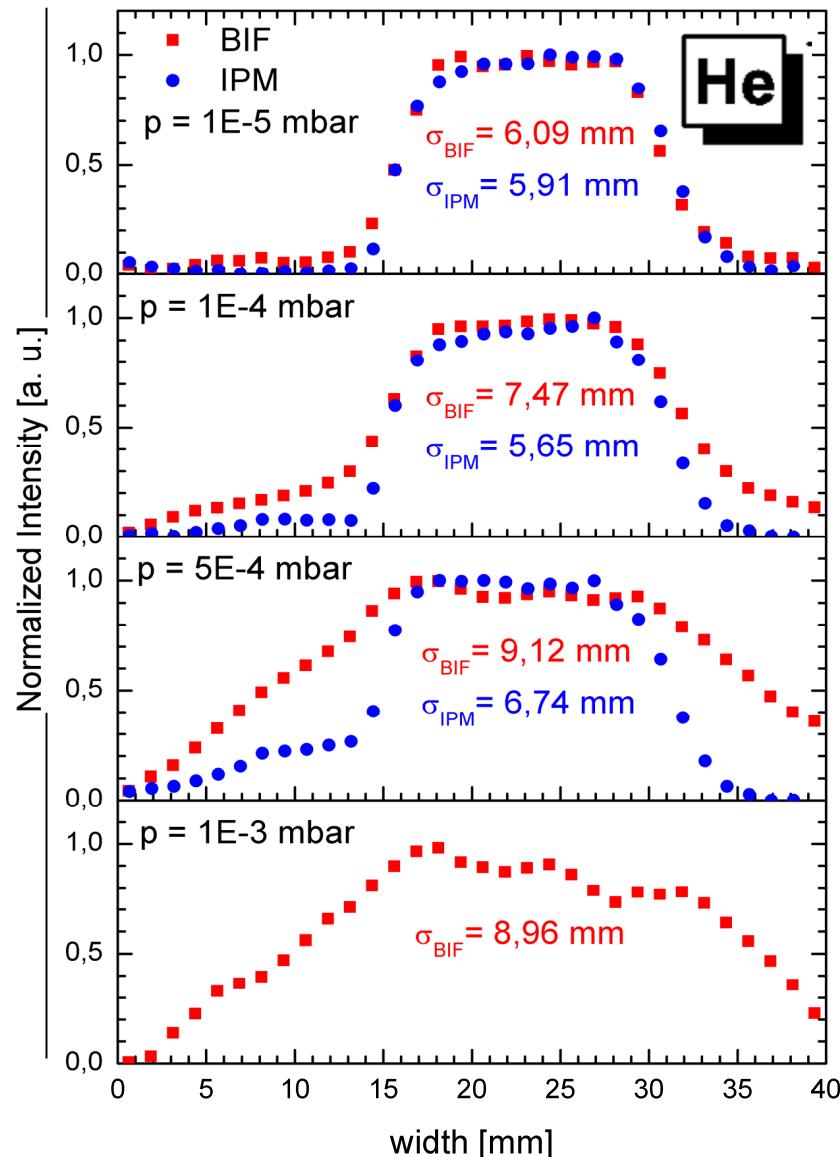
[courtesy of J. Egberts (CEA-Saclay)]

# BIF-IPM Comparison $10^{-5}$ mbar



- Profile data recorded for same spatial regions and matched statistical increments
- 2<sup>nd</sup> statistical moment was obtained in presented range
- Very good agreement of all beam profiles @  $10^{-5}$  mbar and the applied gases

# BIF-IPM Comparison for rising p



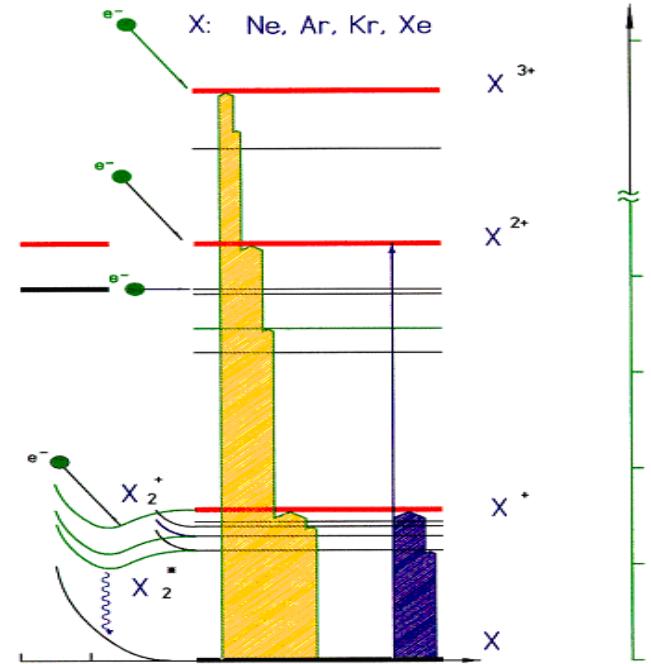
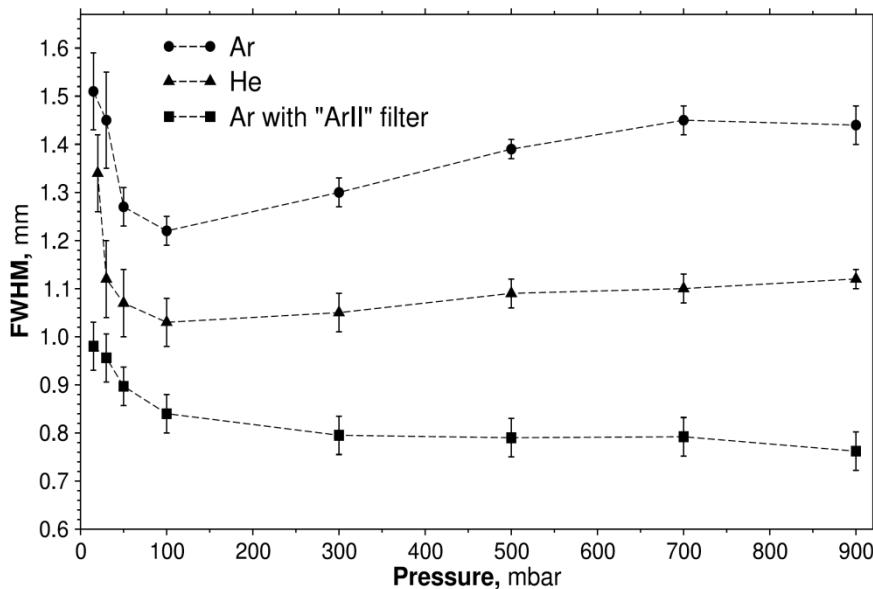
- Profile data recorded for same spatial regions and matched statistical increments
- 2<sup>nd</sup> statistical moment was obtained in presented range
- Very good agreement of all beam profiles @  $10^{-5}$  mbar and the applied gases
- Drastic discrepancy for rising pressure in He and other gases

For high pressure application a systematic study was mandatory

# Studies in Atmospheric Pressure

[A. Ulrich - habilitation 1998]

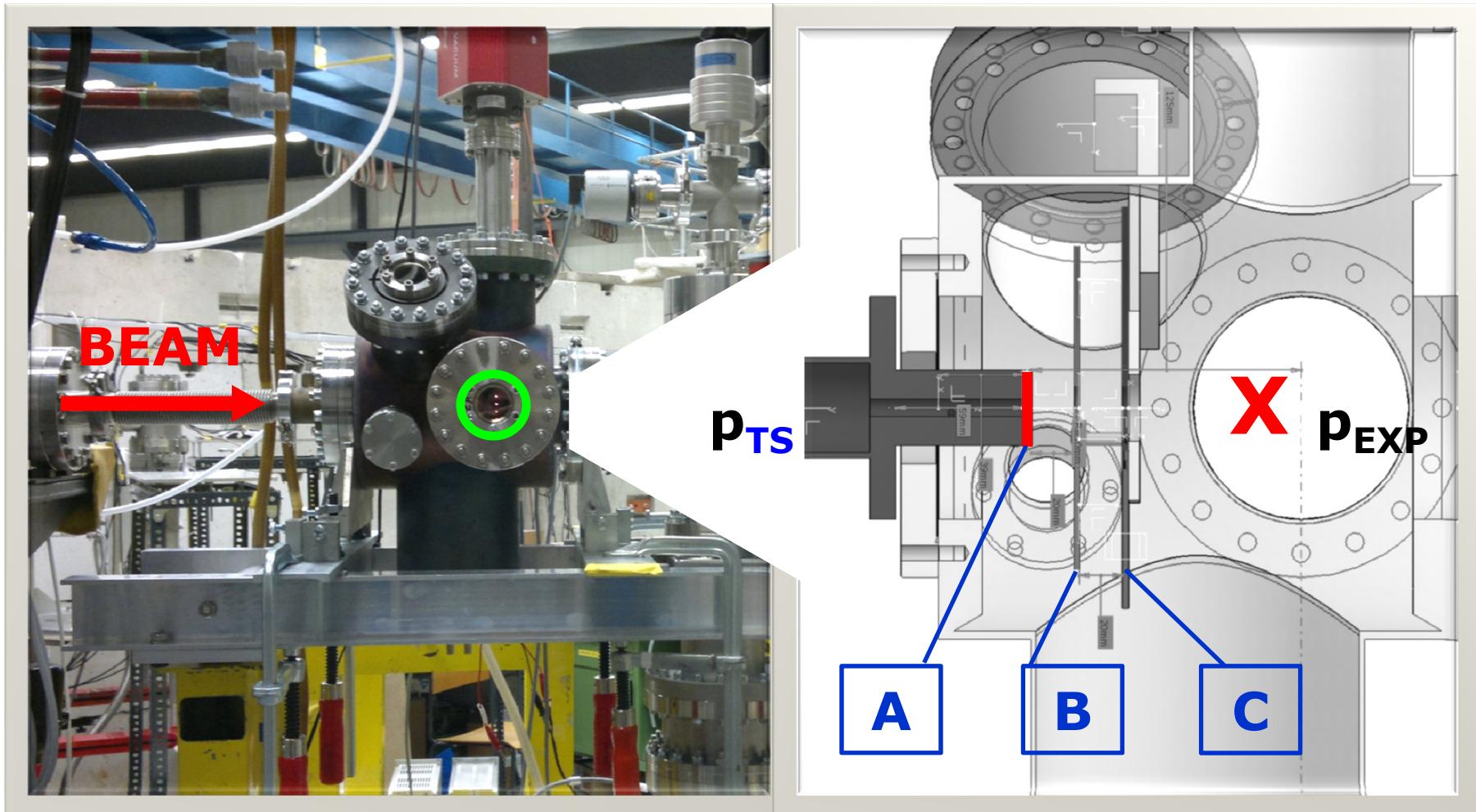
- cross section ratio  $e^-/\text{HI-excitation}$  decreases with degree of ionization
- Therefore profile reading in ionized gases should have higher accuracy



[D. Varentsov et al. CPP-J 2008]

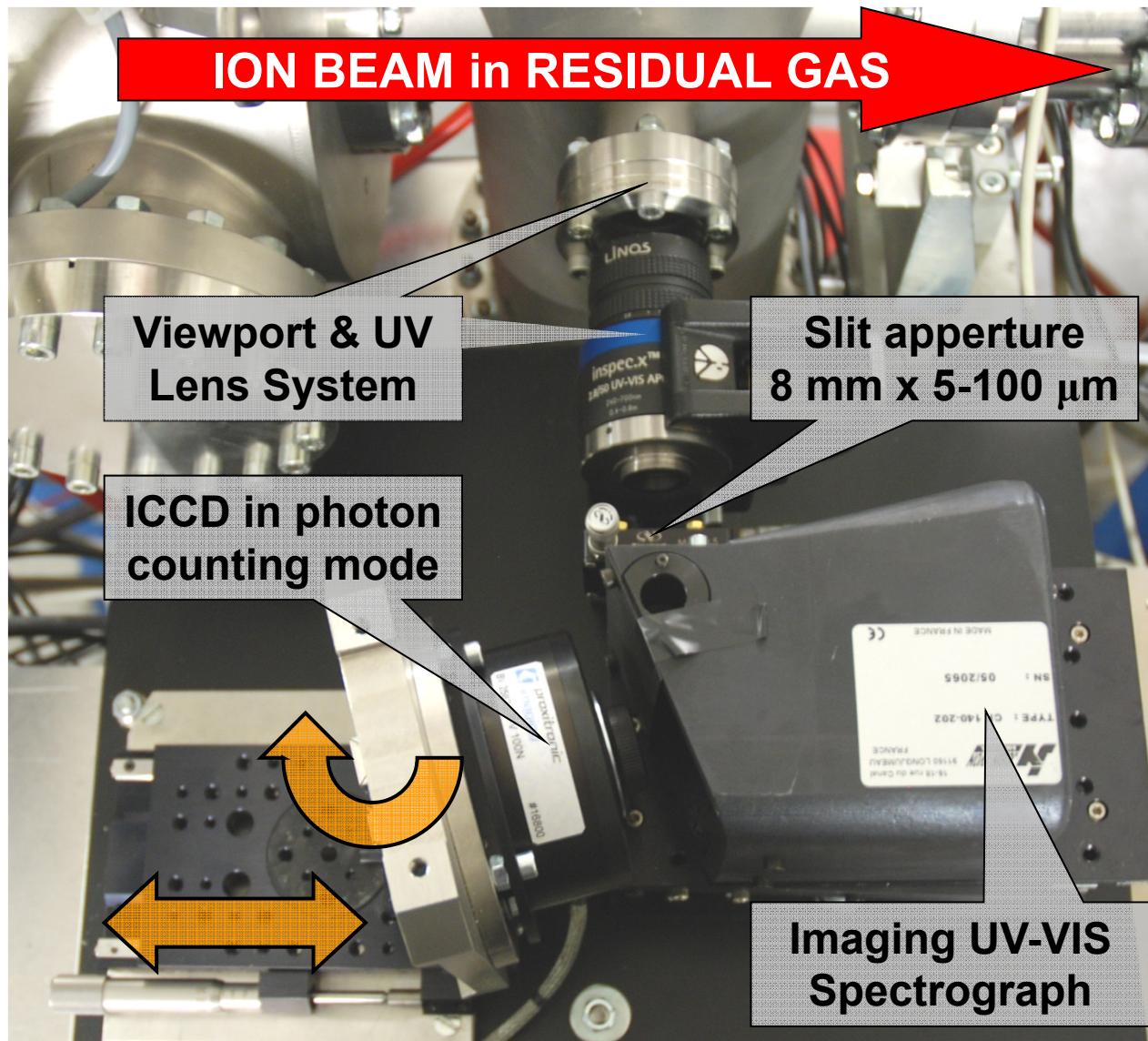
- BIF works for  $p \geq 50$  mbar
- Only ArII lines @ 458 nm provide correct profile reading

# Experimental Setup MLL Garching

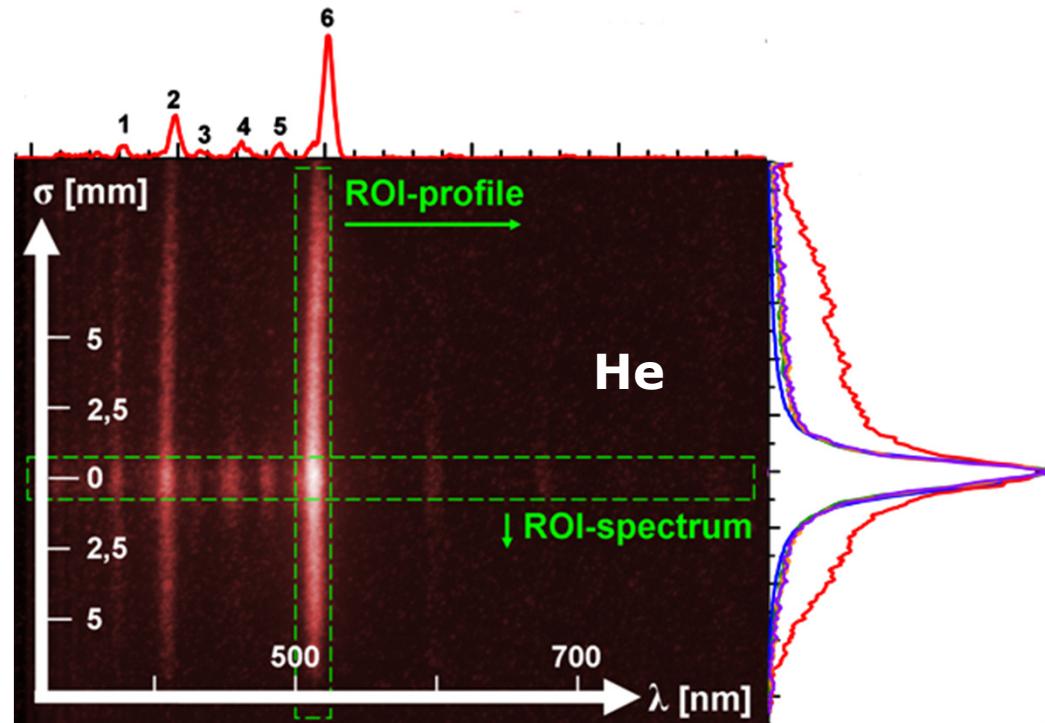
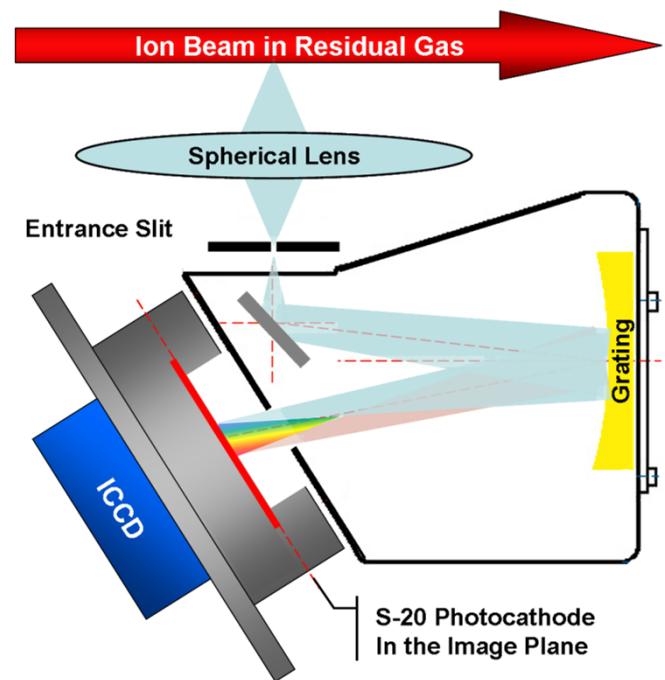


A: Ti-window 1.1 mg/cm<sup>2</sup> | B,C: repeller plates | X: optical center

# Imaging Spectrograph - Setup



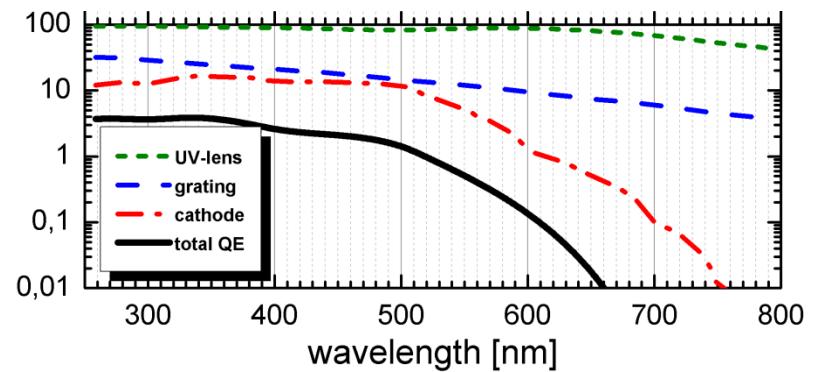
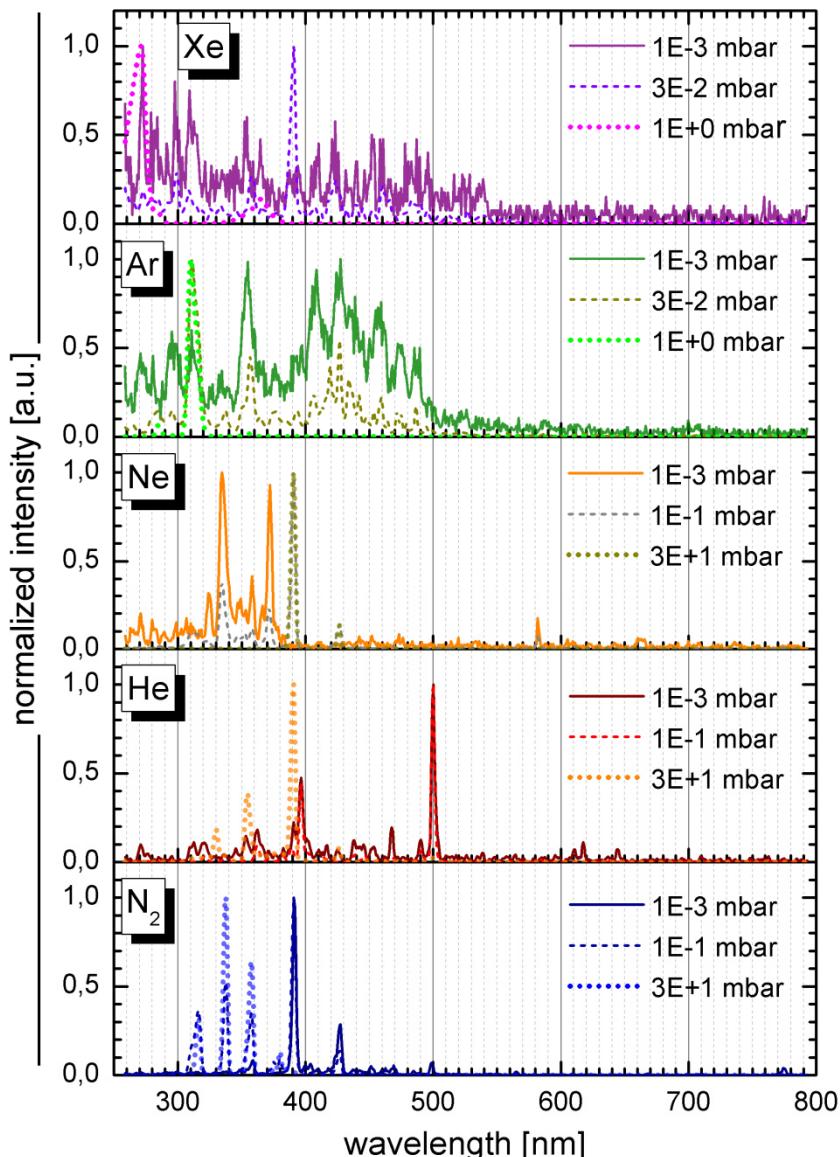
# Imaging Spectrograph with ICCD



- Technique allows to record fluorescence-images with spectral and spatial information (profiles and spectra)
- Chromatically corrected quartz-optics (300 – 800 nm)

Intensity & spectral position of transitions → profile-width

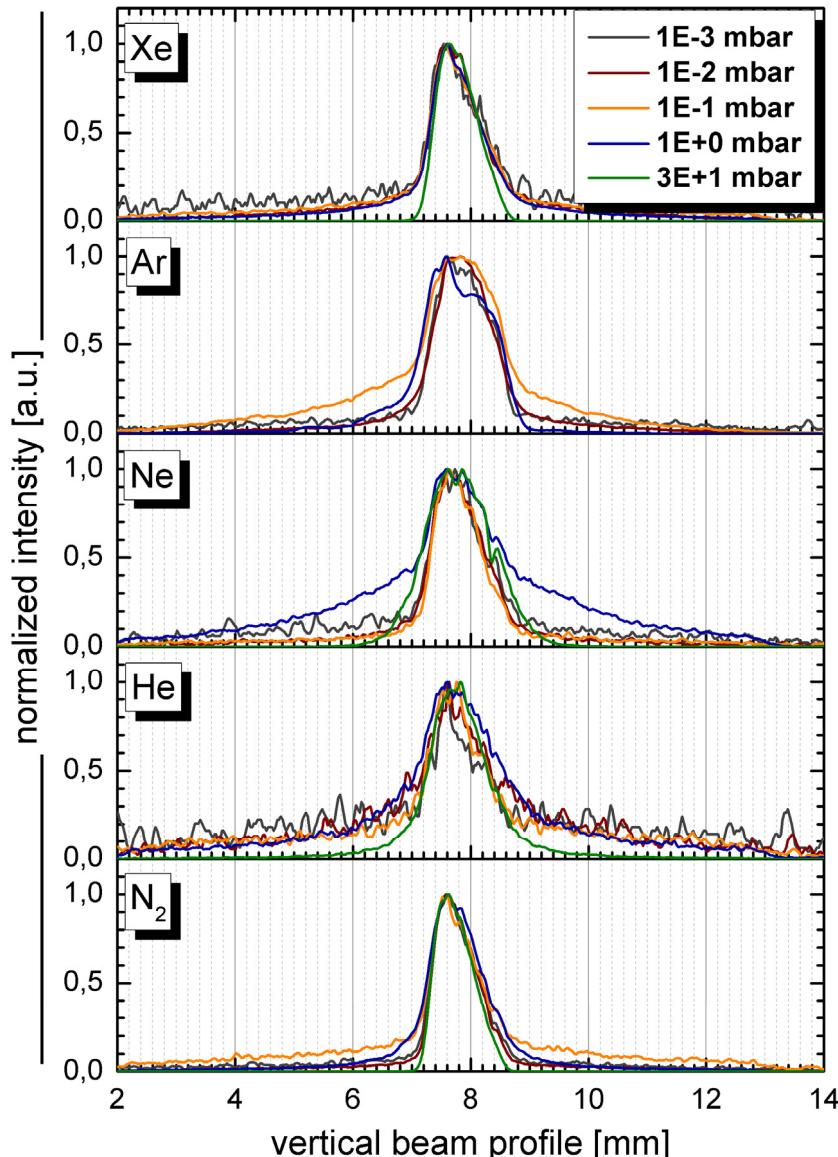
# Fluorescence Spectra in Various Gases



- Spectral response (semi-log)
- Observed spectra for minimal and maximal pressures
- Drastic change in all spectra
- Nitrogen impurities observable in all rare gas species
- Hydroxide ( $\text{OH}^*$ ) in Argon
- Nitrogen changes from ionic  $\text{N}_2^+$  to neutral transitions  $\text{N}_2$

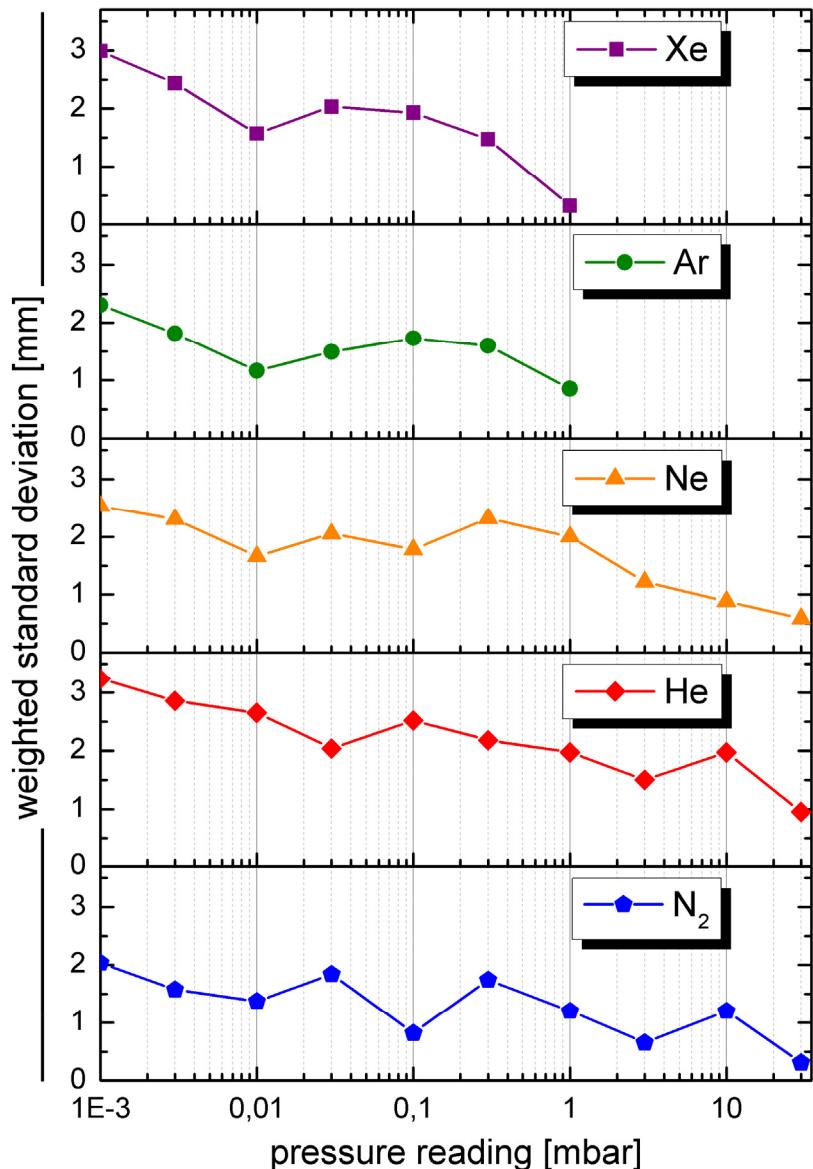
AP processes change completely

# Beam Profiles in Various Gases



- Beam profiles for full p-sweep without spectral line selection
- Nitrogen looks most stable, but all gases falsify profiles
- Core region is less affected, shoulders appear  $\geq 10^{-3}$  mbar
- Smallest profiles were observed for the highest pressure setting

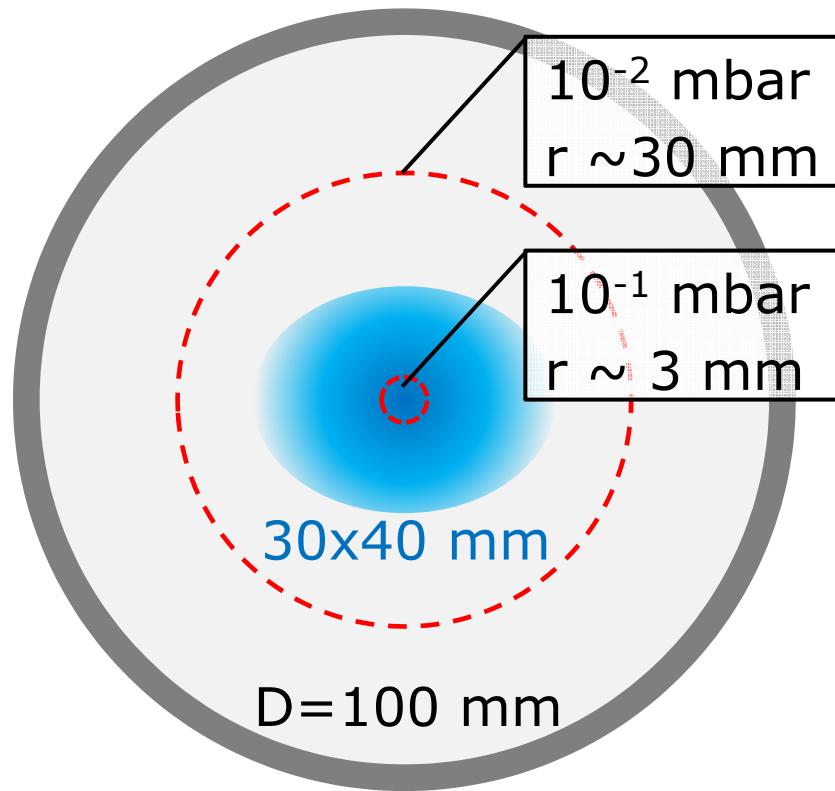
# Beam Profiles in Various Gases



- Beam profiles for full p-sweep without spectral line selection
- Nitrogen looks most stable, but all gases falsify profiles
- Core region is less affected, shoulders appear  $\geq 10^{-3}$  mbar
- Smallest profiles were observed for the highest pressure setting
- 2<sup>nd</sup> statistical moments show profile hump for intermediate p

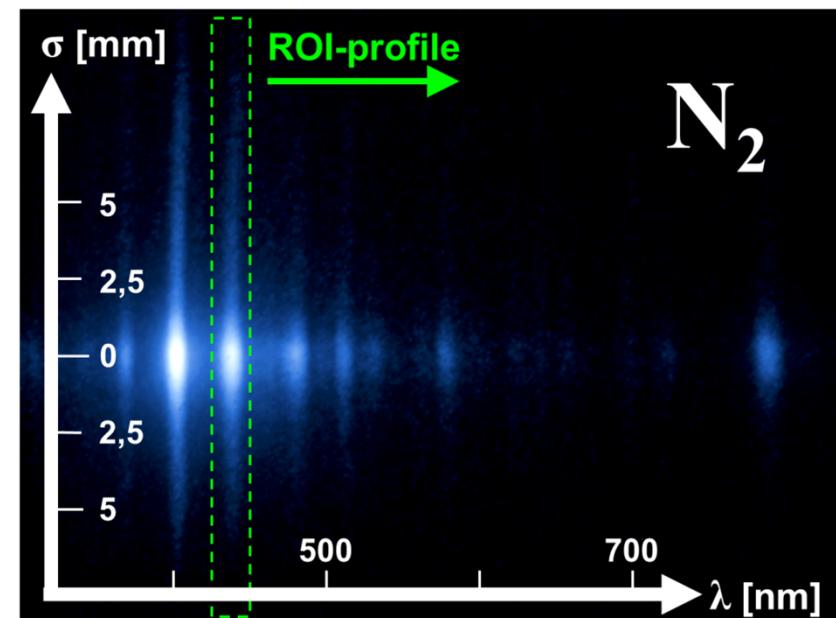
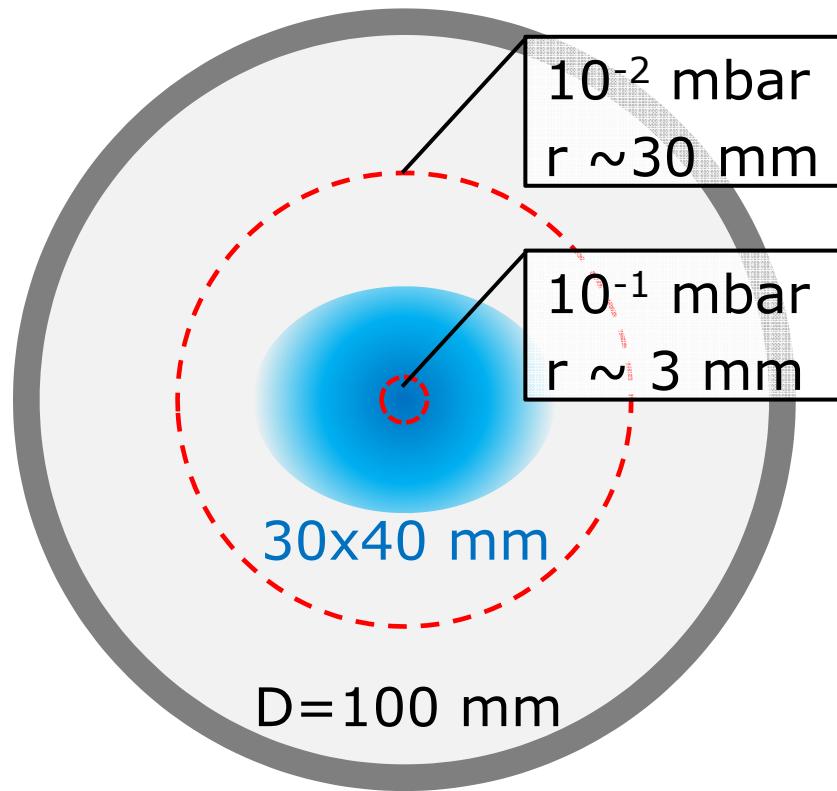
How can unwanted excitation mechanisms be excluded?

# Mean Free Path – Spectral Selection



- For small MFP spontaneous de-excitation replaced by collisional
- Secondary electron halo excites transitions with different CS

# Mean Free Path – Spectral Selection



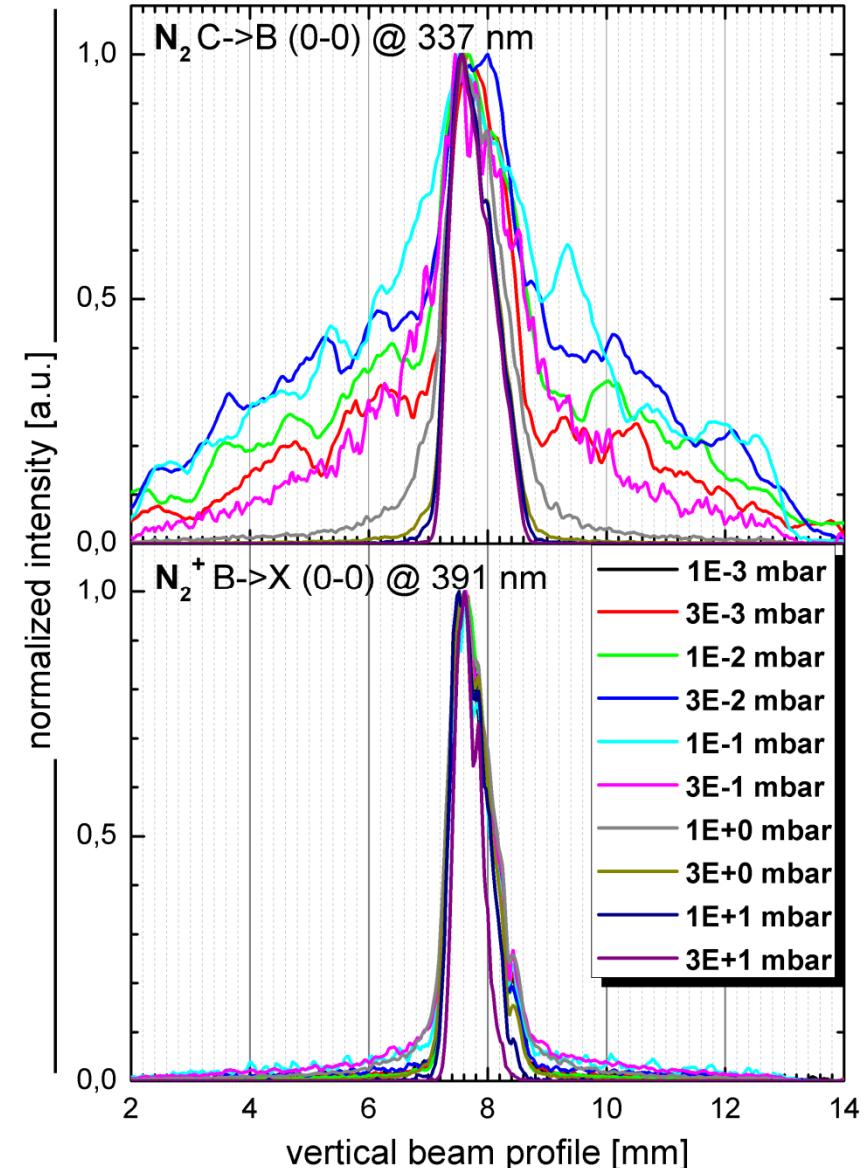
- For small MFP spontaneous de-excitation replaced by collisional
- Secondary electron halo excites transitions with different CS
- Region of interest to observe profiles of single transitions (8nm spectral acceptance)

# Transition Selective Profile Analysis N<sub>2</sub>



- Spectral acceptance (ROI) 8 nm to select transitions separately
- Profiles of neutral transition N<sub>2</sub> show in- and decreasing halo (one tick is 200 μm)
- Profiles of ionic transition N<sub>2</sub><sup>+</sup> unchanged from 10<sup>-3</sup> to 30 mbar
- Fluorescence light in rare gases distributed among several lines but similar tendency is observed

N<sub>2</sub><sup>+</sup> B→X (0-0) should be selected

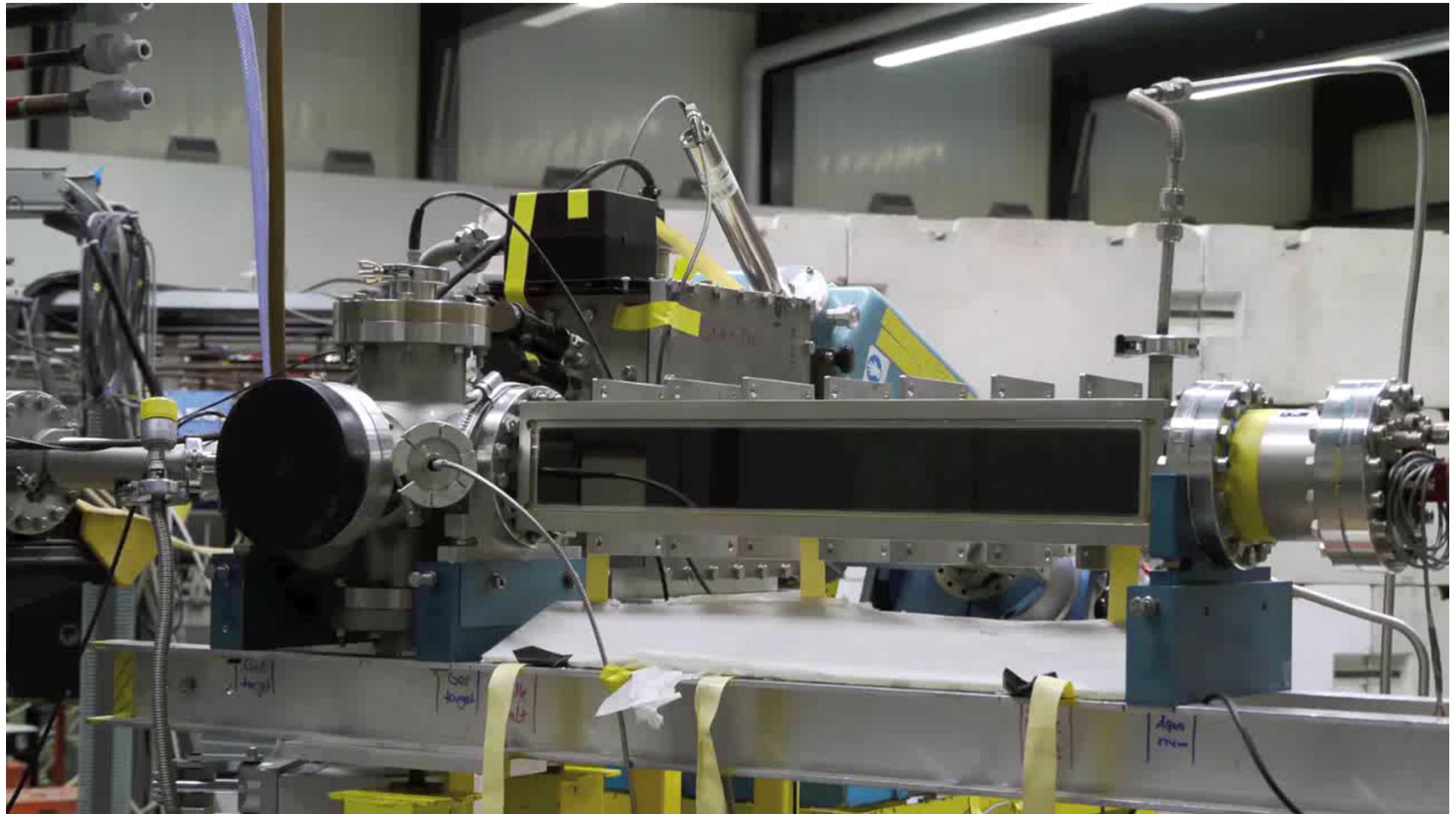


# Conclusion



- **Online profile instrumentation at FAIR:**
  - will be gas based detectors like IPM and BIF monitor
- **Results of research:**
  - BIF and IPM profiles agree very well for  $p \leq 10^{-4}$  mbar
  - BIF spectra and profiles change drastically for increasing  $p$
  - Observed profile hump shows the full image acc. former studies
  - 2<sup>nd</sup> electron halo explains profile halo in neutral transitions
  - Spectral selection of ionic transitions avoids distortions
- **Successful implementation of BIF-monitors:**
  - In the energy-range of 7,5 AkeV – 450 AGeV (former studies)
  - Now we showed application for mbar pressures and beyond
  - BIF monitors and IPMs cover FAIR requirements

# Decreasing Kr-Pressure 1000 – 1 mbar



# Acknowledgements



Thank you for your attention! 😊